

Description

The LMFB7N65 is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

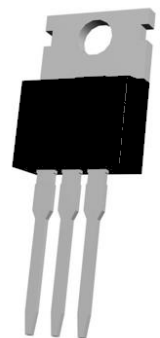
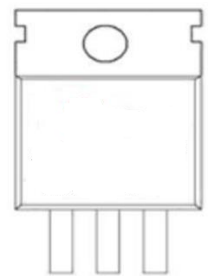
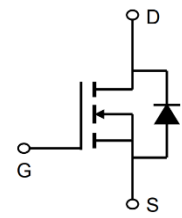
$V_{DS} = 650V$ $I_D = 7A$

$R_{DS(ON)} < 1.2\Omega$ @ $V_{GS}=10V$ (Type: 1.0Ω)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
LMFB7N65	TO-220	AP7N65F XXX YYYY	1000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value		Unit
		TO-220F	TO-220	
V_{DS}	Drain-Source Voltage ($V_{GS} = 0V$)	650		V
I_D	Continuous Drain Current	7		A
I_{DM}	Pulsed Drain Current (note1)	28		A
V_{GS}	Gate-Source Voltage	± 30		V
E_{AS}	Single Pulse Avalanche Energy (note2)	247		mJ
I_{AR}	Avalanche Current (note1)	7		A
E_{AR}	Repetitive Avalanche Energy note1)	18		mJ
P_D	Power Dissipation ($T_C = 25^\circ C$)	32.9		W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55~+150		$^\circ C$
R_{thJC}	Thermal Resistance, Junction-to-Case	3.8		$^\circ C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	13.3		$^\circ C/W$

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	650	685	--	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 650V, V _{GS} = 0V, T _J =25°C	--	--	1	μA
IGSS	Gate-Source Leakage	V _{GS} = ±30V	--	--	±100	nA
VGS(th)	Gate-Source Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	--	4.0	V
RDS(on)	Drain-Source On-Resistance (Note3)	V _{GS} = 10V, I _D = 3.5A	--	1.0	1.2	Ω
C _{iss}	Input Capacitance	V _{GS} = 0V, V _{DS} = 25V, f = 1.0MHz	--	1000	--	pF
C _{oss}	Output Capacitance		--	101	--	
C _{rss}	Reverse Transfer Capacitance		--	1.5	--	
Q _g	Total Gate Charge	V _{DD} =520V, I _D = 7A, V _{GS} = 10V	--	22	--	nC
Q _{gs}	Gate-Source Charge		--	4.3	--	
Q _{gd}	Gate-Drain Charge		--	13	--	
td(on)	Turn-on Delay Time	V _{DD} =325V, I _D = 7A, R _G = 25Ω	--	12	--	ns
t _r	Turn-on Rise Time		--	26	--	
td(off)	Turn-off Delay Time		--	29	--	
t _f	Turn-off Fall Time		--	27	--	
I _S	Continuous Body Diode Current	T _C = 25 °C	--	--	7.0	A
I _{SM}	Pulsed Diode Forward Current		--	--	28	A
V _{SD}	Body Diode Voltage	T _J = 25°C, I _{SD} = 7A, V _{GS} = 0V	--	--	1.4	V
trr	Reverse Recovery Time	V _{GS} = 0V, I _S = 7A, di _F /dt = 100A/μs	--	389	--	ns
Q _{rr}	Reverse Recovery Charge		--	2.04	--	μC

Note :

- 1、 The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2、 The EAS data shows Max. rating . I_{AS} = 4.5A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25 °C
- 3、 The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

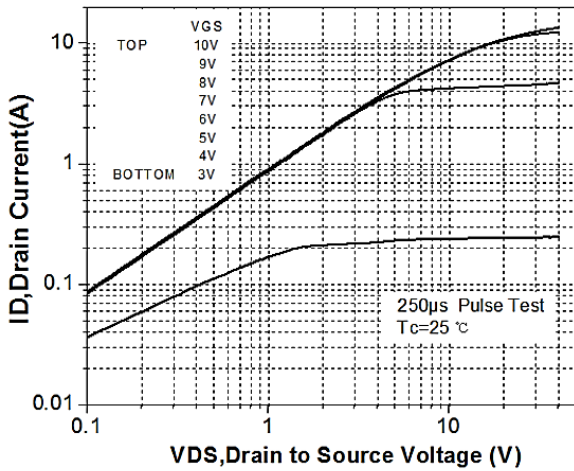


Figure 1. On-Region Characteristics

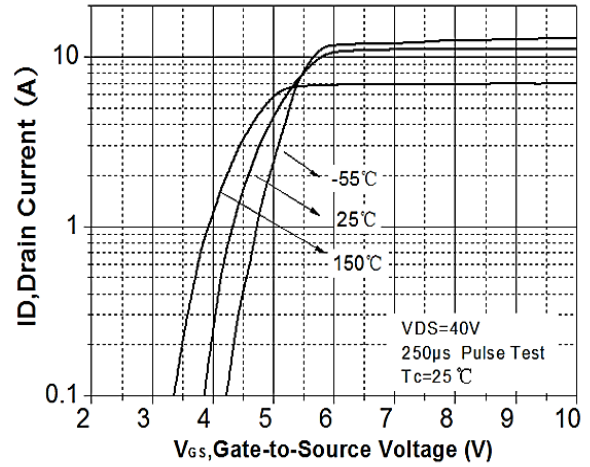


Figure 2. Transfer Characteristics

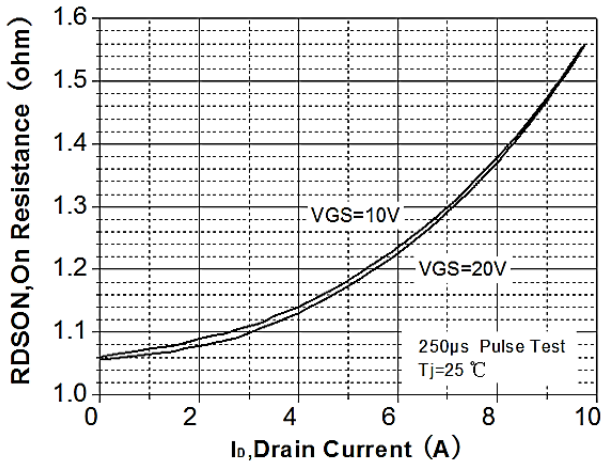


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

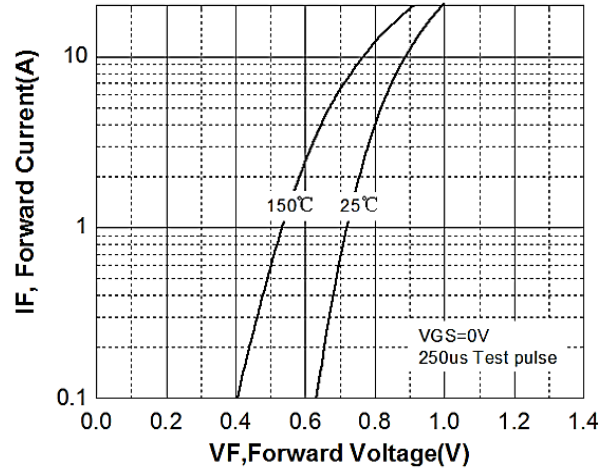


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

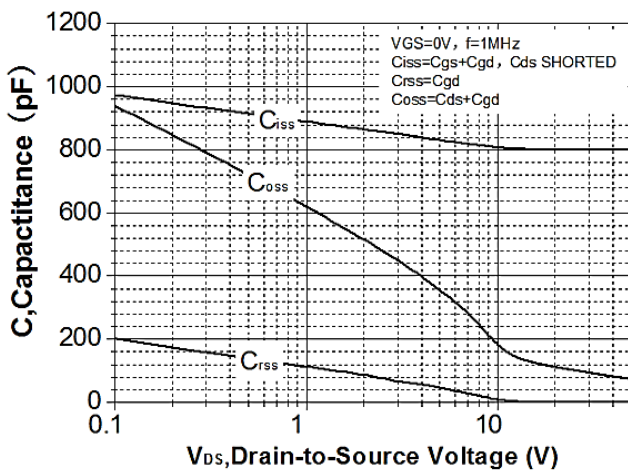


Figure 5. Capacitance Characteristics

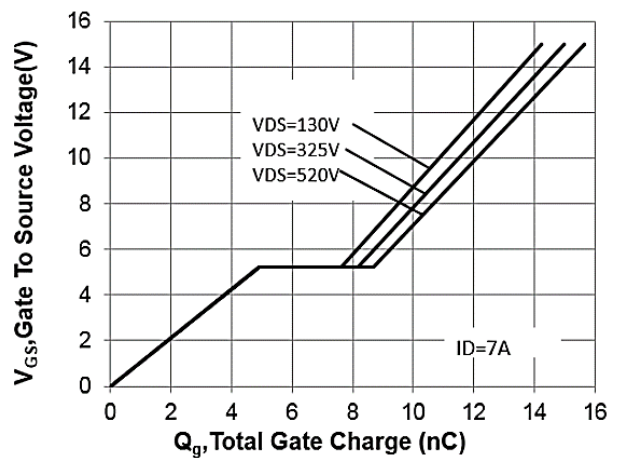


Figure 6. Gate Charge Characteristics

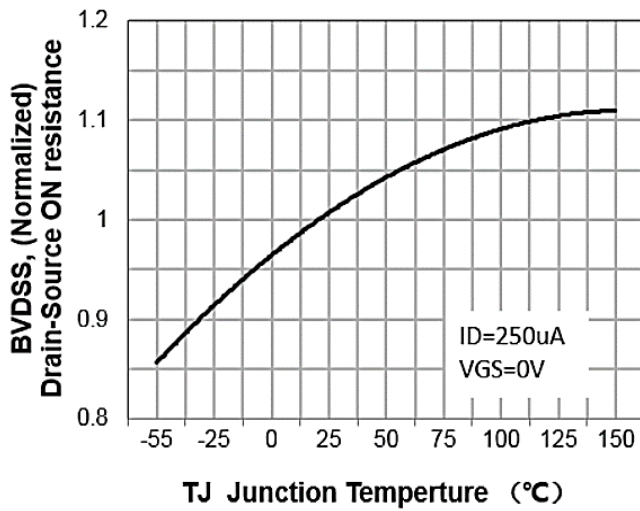


Figure 7. Breakdown Voltage Variation vs Temperature

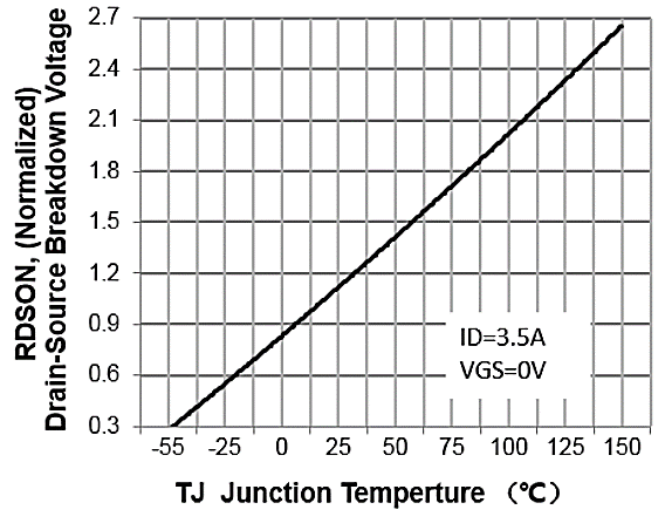


Figure 8. On-Resistance Variation vs Temperature

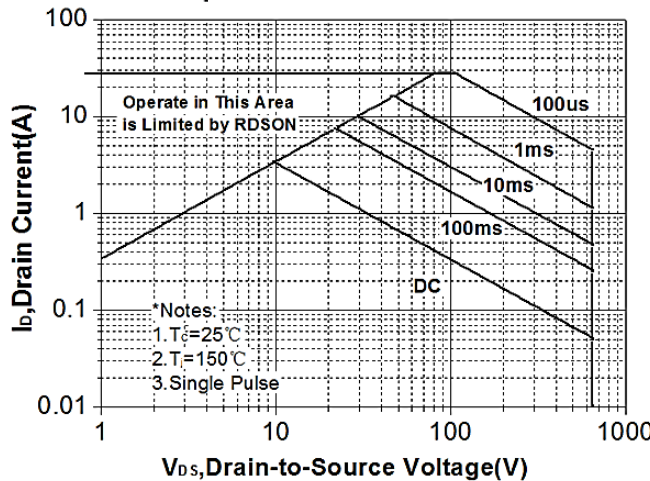


Figure 9. Maximum Safe Operating Area

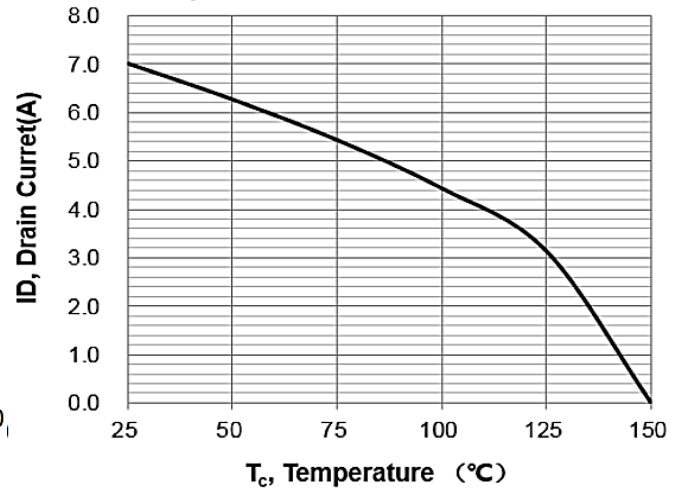


Figure 10. Maximum Drain Current vs Case Temperature

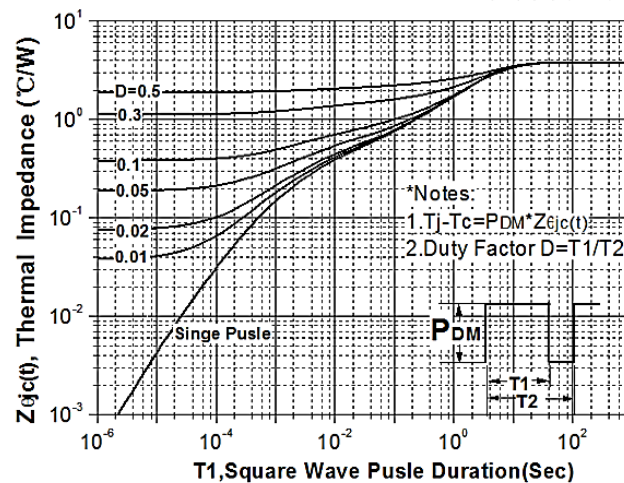


Figure 11. Transient Thermal Response Curve

